

# NEW AND/OR INTERESTING IN MICROSCOPY

## CONGRATULATIONS TO THE NEW OFFICERS OF MSA AND MAS:

### *Microscopy Society of America:*

President-Elect Tony Mitchell (Los Alamos National Laboratories)  
 Secretary (Reelected): Barbara Reine (University of Washington)  
 Physical Science Director: Ernie Hall (General Electric)  
 Biological Science Director: Conly L. Rieder (New York State Dept. Health)  
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### *Microbeam Analysis Society:*

President-Elect: Jon McCarthy (Noran Instruments)  
 Director: Paul Hlava (Sandia National Laboratories)  
 Director: Carol W. Swyt (National Institute of Health)

★ *Advanced Imaging Magazine*, now in its 9th year, is the world's leading publication regarding all forms and uses of image processing. Features regularly include microscopy imaging and image analysis. Free to professionals. For free subscription application form, Fax request to: (516)845-2797 and specify *Advanced Imaging Magazine*.

★ In response to popular demand, Arizona State University will hereafter be offering its workshop on materials TEM specimen preparation on a quarterly basis. The next workshop of this series is scheduled for April 11-13, 1994. Additionally, a new and more advanced related workshop will precede the above which consists of two independent segments, i.e., site-specific/precision cross-sectioning (March 14-16, 1994) and materials ultramicrotomy (March 17-18, 1994). Prospective participants may register for either or both segments. For further information, contact Dr. Farhad Shaapur at (602)965-0399.

★ KeveX has introduced a large area (30 mm<sup>2</sup>) SuperDry EDS detector which affords Analytical TEM users a light weight alternative with no compromise in solid angle. As always, customers that don't wish to handle LN on EMs will now have an additional choice for "count poor" samples. Fisons Instruments Mfg., Inc.: (805)295-0019.

★ MVA, Inc., is pleased to announce that Dr. Lindsay P. Keller has joined the staff. Lindsay plans to continue his NASA supported research into the chemistry of extra-terrestrial materials and to undertake contract research in materials characterization for MVA's industrial clients. Lindsay can be reached at 404-662-8509.

★ FEI Company has moved to their new world headquarters at 7451 N.E. Evergreen Parkway, Hillsboro, OR 97124. With 44,000 square feet, nearly twice the size of their previous facility, the new facility significantly increases FEI's manufacturing capacity as well as providing expanded demonstration and customer training facilities.

★ The Royal Microscopical Society announces it's 1994 course schedule: **Digital Imaging Light Microscopy Summer School** (10/15 July 1994) at the Univ. of Liverpool.

**Summer School in Light Microscopy** (17/22 July 1994) at Univ. of Leeds.  
**Ultrastructural Immunocytochemistry Course** (14/18 November 1994) at the Institute of Cancer Research, Sutton.

**Immunocytochemistry Course** (4/9 September 1994) at Oxford Brookes University, Oxford.

**Flow Cytometry Course** (19/21 September 1994) at Univ. of Cambridge.  
 For further details, contact the RMS - telephone +44 (0)865 248768, Fax +44 (0)865 791237, eMail RMS@UK.AC.OX.VAX.

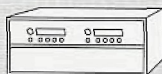
★ Leybold Vacuum Products, Inc. has recently named Richard T. Heglin as President and CEO and Ken Kalia as Vice President, Sales and Marketing. Mr. Heglin was previously Vice President and General Manager of Superior Valve Company and Mr. Kalia was Vice President of Marketing and Sales with Aurora Pump, a unit of General Signal.

★ New from xk, Incorporated: Fuzzy Logic Automated Microanalysis Engine (FLAME™) EDS software for the Macintosh provides for fast (< 2 seconds) and accurate automatic results. Uses Fuzzy Logic and AI to rapidly improve identification and quantification over standard rule-based EDS systems. For further information, contact xk, Incorporated at tel.: (415)349-1301, Fax: (415)349-1185.

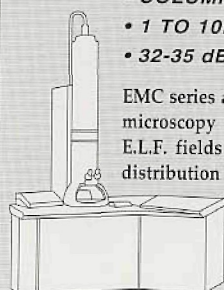
★ Gatan R&D will hold a TEM Specimen School on May 2/4, 1994 in Pleasanton, CA. The extensive, practical course has been designed to teach material scientists the art and science of TEM specimen preparation. The course will concentrate on the various ion milling techniques not available and will show how excellent TEM specimens can be produced from almost any material encountered by the materials scientist. For further information, contact Reza Alani - Tel.: (510)463-0200, Fax: (510)463-0204.

★ Now in its 10th year, the North Carolina State University 3-day short course and workshop **Computer-Assisted Image Analysis and Measurement** will be held on May 17-19, 1994 in Raleigh, NC. The course is intended to familiarize users of image analysis equipment with the fundamental principles and methods available to obtain meaningful results, and to educate laboratory supervisors or research professionals seeking to learn how to use such methods in their applications. The techniques are applicable to fields ranging from materials, geological and biological research to food technology and manufacturing quality control. For further information, contact Joni Tanner at (919)515-2261.

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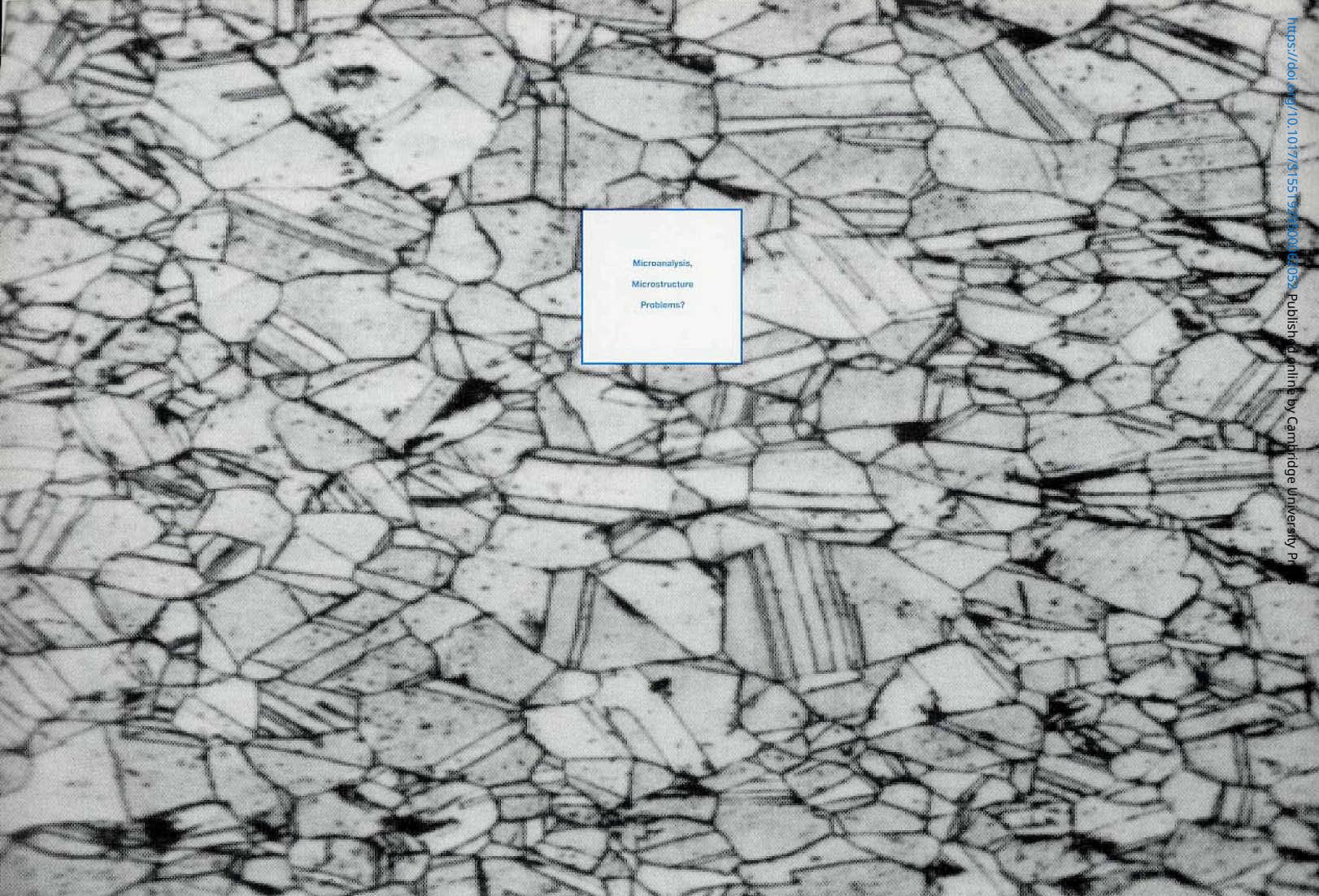
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